

IN THE CLAIMS:

1. (original) A method of generating a deep N-well pattern for an integrated circuit design, said method comprising:

specifying a tile comprising a first layer wherein said first layer

comprises a first layer element for a deep N-well pattern;

arranging multiple instances of said tile to create a tile array covering a portion of said integrated circuit design; and

merging said tiles to produce a deep N-well pattern.

2. (original) The method of Claim 1, wherein said tile further comprises a second layer, wherein said second layer comprises a second layer element.

3. (original) The method of Claim 2, wherein said first layer element is identical in shape to said second layer element.

4. (original) The method of Claim 3, wherein said first layer element is disposed rotated with respect to said second layer element.

5. (original) The method of Claim 1, further comprising editing said tile array.

Claims 6-7 (canceled) (restriction)

8. (original) The method of Claim 2, further comprising flattening said first layer and said second layer.

Claims 9-24 (canceled) (restriction)

25. (new) A method of generating a deep N-well pattern for an integrated circuit design, said method comprising:

specifying a tile comprising a first layer wherein said first layer comprises a first layer element for a deep N-well pattern;

arranging multiple instances of said tile to create a tile array covering a portion of said integrated circuit design; and

merging said multiple instances of said tiles to produce a deep N-well pattern, wherein said deep N-well pattern is operable to provide body-bias voltage connections within said integrated circuit design.

26. (new) The method of Claim 25, wherein said tile further comprises a second layer, wherein said second layer comprises a second layer element.

27. (new) The method of Claim 26, wherein said first layer element is identical in shape to said second layer element.

28. (new) The method of Claim 27, wherein said first layer element is disposed rotated with respect to said second layer element.
29. (new) The method of Claim 25, further comprising editing said tile array.
30. (new) The method of Claim 26, further comprising flattening said first layer and said second layer.
31. (new) A method of generating a deep N-well pattern for an integrated circuit design, said method comprising:
- specifying a tile means comprising a first layer wherein said first layer comprises a first layer element for a deep N-well pattern;
  - arranging multiple instances of said tile means to create a tile array means covering a portion of said integrated circuit design; and
  - merging said multiple instances of said tile means to produce a deep N-well pattern, wherein said deep N-well pattern is operable to provide body-bias voltage connections within said integrated circuit design.
32. (new) The method of Claim 31, wherein said tile means further comprises a second layer, wherein said second layer comprises a second layer element.

33. (new) The method of Claim 32, wherein said first layer element is identical in shape to said second layer element.
34. (new) The method of Claim 33, wherein said first layer element is disposed rotated with respect to said second layer element.
35. (new) The method of Claim 31, further comprising editing said tile array.
36. (new) The method of Claim 32, further comprising flattening said first layer and said second layer.